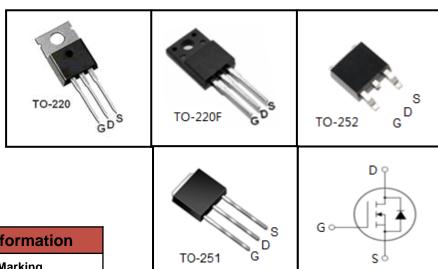
### **600V N-Channel MOSFET**

#### **FEATURES**

- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

#### **APPLICATIONS**

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)



<b>Device Marking and Package Information</b>					
Device	Package	Marking			
CS8N60F	TO-220F	CS8N60F			
CS8N60P	TO-220	CS8N60P			
CS8N60U	TO-251	CS8N60U			
CS8N60D	TO-252	CS8N60D			

<b>Absolute Maximum Ratings</b> T <sub>C</sub> = 25°C, unless otherwise noted						
Baramatar	Ob-s-l		11			
Parameter	Symbol	TO-220F	TO-220	TO-251	TO-252	Unit
Drain-Source Voltage (V <sub>GS</sub> = 0V)	V <sub>DSS</sub>	600			V	
Continuous Drain Current	I <sub>D</sub>	8			Α	
Pulsed Drain Current (note1)	I <sub>DM</sub>	32			Α	
Gate-Source Voltage	V <sub>GSS</sub>	±30		V		
Single Pulse Avalanche Energy (note2)	E <sub>AS</sub>	217.8			mJ	
Avalanche Current (note1)	I <sub>AR</sub>	6.6			Α	
Repetitive Avalanche Energy (note1)	E <sub>AR</sub>	130.6			mJ	
Power Dissipation (T <sub>C</sub> = 25°C)	P <sub>D</sub>	54 83		W		
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55~+150				°C

Thermal Resistance						
Baramatar	Symbol	Value				11
Parameter		TO-220F	TO-220	TO-251	TO-252	Unit
Thermal Resistance, Junction-to-Case	R <sub>thJC</sub>	1.95		1.17		K/W
Thermal Resistance, Junction-to-Ambient	R <sub>thJA</sub>	62.5	60		TV/VV	



Parameter	Symbol		Value			
		Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0V, I_{D} = 250\mu A$	600			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 600V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	μA
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 30V$			±100	nA
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		4.0	V
Drain-Source On-Resistance (Note3)	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 4A		0.85	1	Ω
Dynamic						
Input Capacitance	C <sub>iss</sub>	V 0V		966		pF
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0V,$ $V_{DS} = 25V,$ f = 1.0MHz		115.5		
Reverse Transfer Capacitance	C <sub>rss</sub>			19.5		
Total Gate Charge	$Q_g$	$V_{DD} = 480V, I_{D} = 8A,$ $V_{GS} = 10V$		35		nC
Gate-Source Charge	$Q_{gs}$			4.5		
Gate-Drain Charge	$Q_{gd}$			18.5		
Turn-on Delay Time	t <sub>d(on)</sub>			38.5		
Turn-on Rise Time	t <sub>r</sub>	$V_{DD} = 300V, I_{D} = 8A,$		28.5		
Turn-off Delay Time	t <sub>d(off)</sub>	$R_G = 25 \Omega$		153		ns
Turn-off Fall Time	t <sub>f</sub>			43.6		
Drain-Source Body Diode Character	istics					
Continuous Body Diode Current	I <sub>s</sub>	_			8	
Pulsed Diode Forward Current	I <sub>SM</sub>	T <sub>C</sub> = 25 °C			32	A
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25^{\circ}C$ , $I_{SD} = 4A$ , $V_{GS} = 0V$			1.4	V
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS} = 0V, I_{S} = 8A,$		575.6		ns
Reverse Recovery Charge	Q <sub>rr</sub>	di <sub>F</sub> /dt =100A /μs		1.96		μC

#### Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L=10mH,  $V_{DD}$  = 50V,  $R_G$  = 25  $\Omega$ , Starting  $T_J$  = 25  $^{\circ}C$
- 3. Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 1%

Drain Current (A)

## CS8N60F,CS8N60P,CS8N60U,CS8N60D

#### **Typical Characteristics** $T_J = 25^{\circ}$ C, unless otherwise noted

Figure 1. Output Characteristics (T<sub>J</sub> = 25°C)

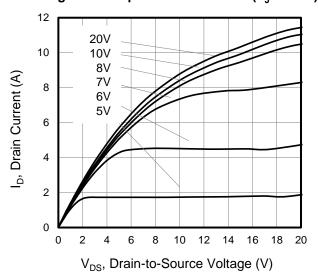


Figure 2. Body Diode Forward Voltage

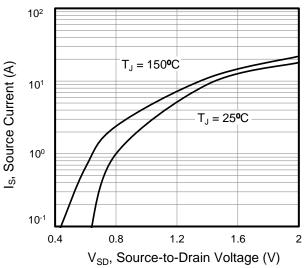


Figure 3. Drain Current vs. Temperature

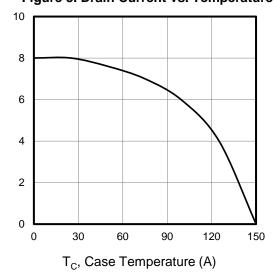


Figure 4. BV<sub>DSS</sub> Variation vs. Temperature

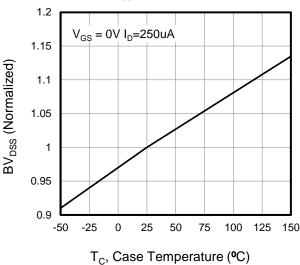


Figure 5. Transfer Characteristics

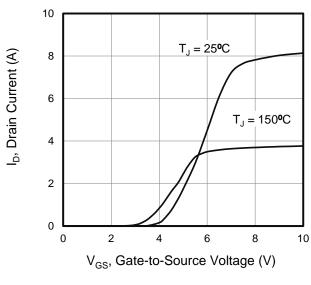
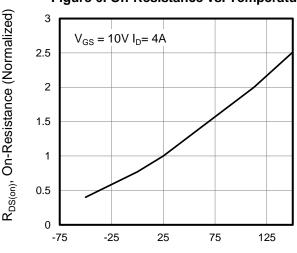


Figure 6. On-Resistance vs. Temperature



### **Typical Characteristics** $T_J = 25^{\circ}C$ , unless otherwise noted

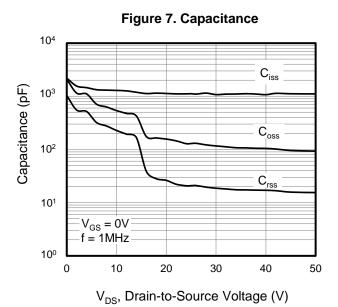


Figure 9. Transient Thermal Impedance TO-251,TO-252

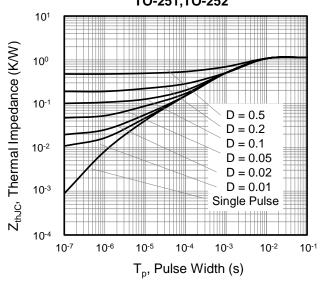


Figure 8. Gate Charge

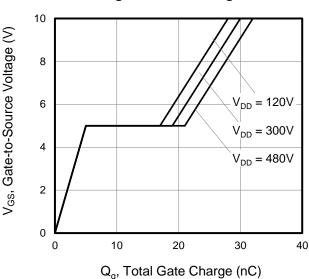


Figure 10. Transient Thermal Impedance

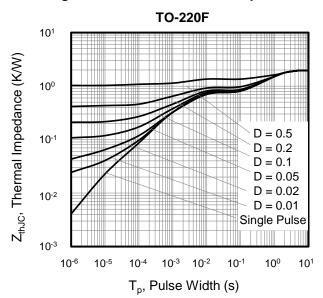


Figure A: Gate Charge Test Circuit and Waveform

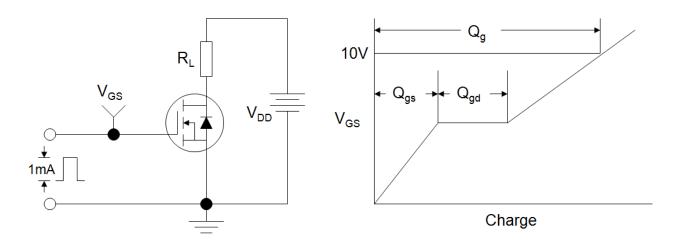


Figure B: Resistive Switching Test Circuit and Waveform

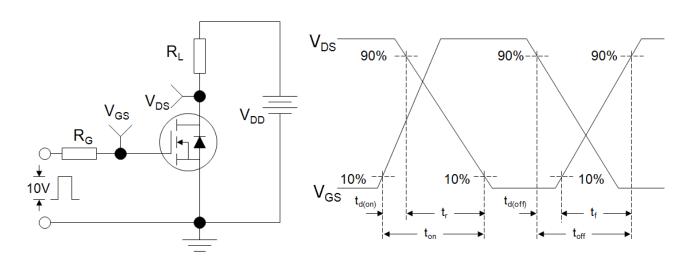
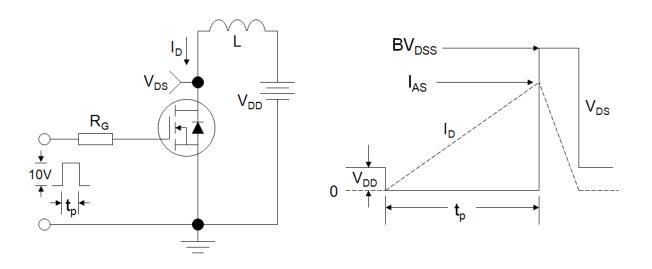


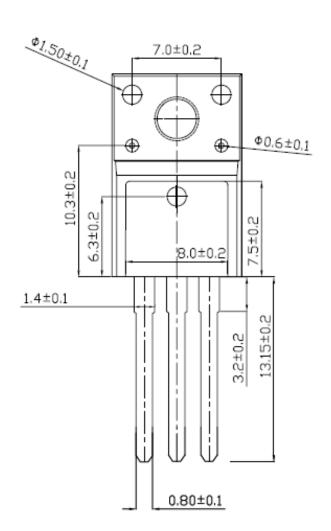
Figure C: Unclamped Inductive Switching Test Circuit and Waveform

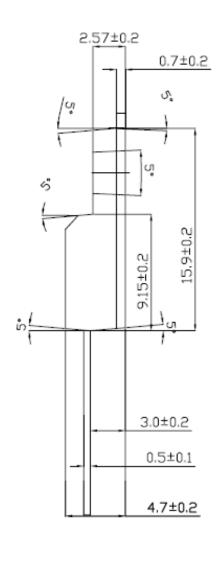




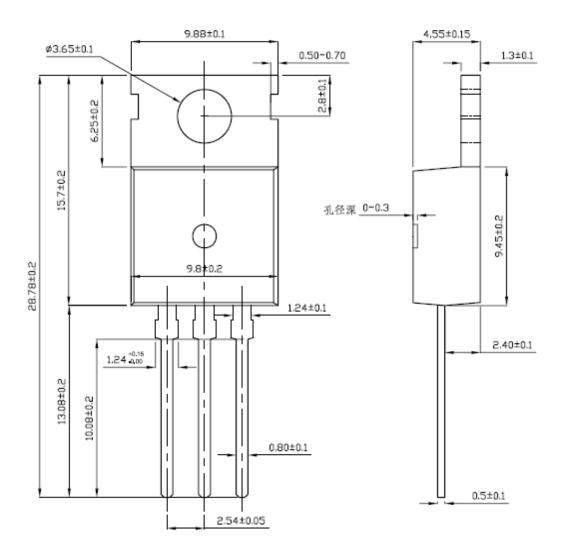
# nvert cs8N60F,CS8N60P,CS8N60U,CS8N60D

## **TO-220F**

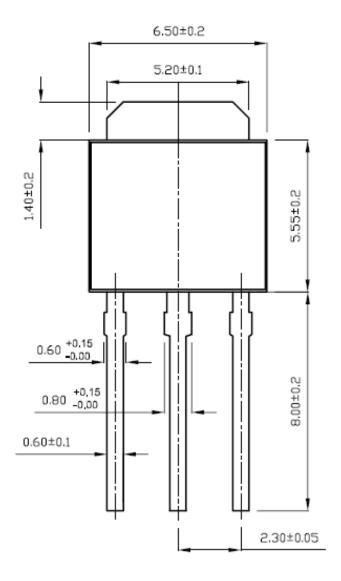


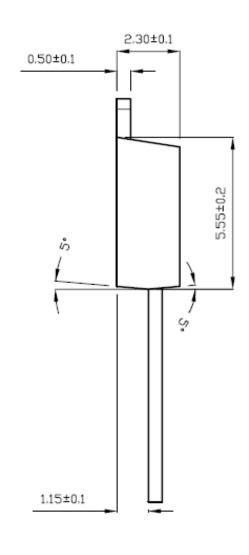


## **TO-220**

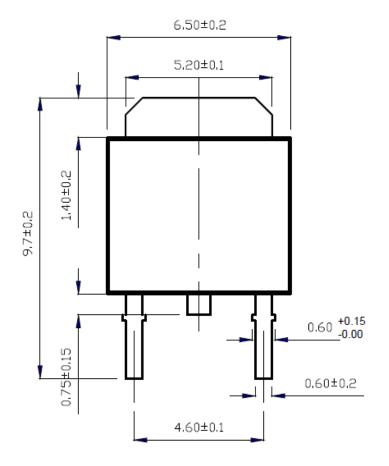


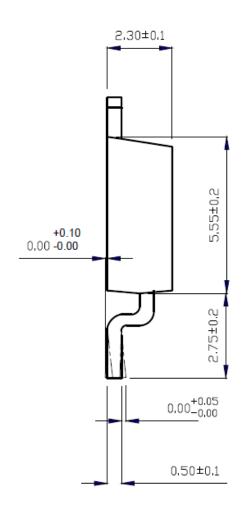
TO-251





## **TO-252**







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